

Amendments to the Specification:

Please replace the paragraph beginning on Page 4, line 21 with the following amended paragraph:

a1 More particularly, the control device 19 may be an external memory array 7, e.g., of the non-volatile type, substantially like that incorporated in the device 1. In another embodiment, the control device 9 may be a control logic 12 substantially like that incorporated in the device 1.

Please replace the paragraph beginning on Page 5, line 7 with the following amended paragraph:

a2 The solution to the problem resides in temporarily "replacing" the cell array 2 with another array 7, external of the device 1, Which is one example of, or a portion of the test operation control device 7, as shown in the drawing. According to the principles of the invention the external array 7 is used to simulate the internal memory 2, making possible the direct test and observation of the interaction of the control logic 4 with the array 7. The external memory array 7 can be an actual hardware memory, identical to the internal memory array 2. Alternatively, it may be a simulated array, having some portions in hardware and some in software, or all portions in software, to simulate the relevant portions and operations of the internal memory array 2. As will be appreciated, the test operation control device 9 may also comprise logic circuitry 12 to simulate the control logic 4, for the purpose of testing and observing the memory array 2 directly, and in isolation from the control logic.